

# Ion Mill Workstation Trio from SPI Supplies®



From TEM cross sections to EBSD final polishing, SPI Supplies has the right tool for all your ion milling sample preparation needs.

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## Technoorg® Linda Sample Preparation System

Ensuring the highest-quality ion beam milling for all types of materials and samples.

### Gentle Mill 3

**A unique sample preparation process for final polishing and cleaning.**

The Gentle Mill series has been designed for final polishing, easy cleaning and improving the quality of samples previously treated in standard high-energy ion mills or FIB columns. Gentle Mill models are recommended for users who want to prepare artifact- and damage-free XTEM, HRTEM, STEM or SEM samples of the best possible quality.

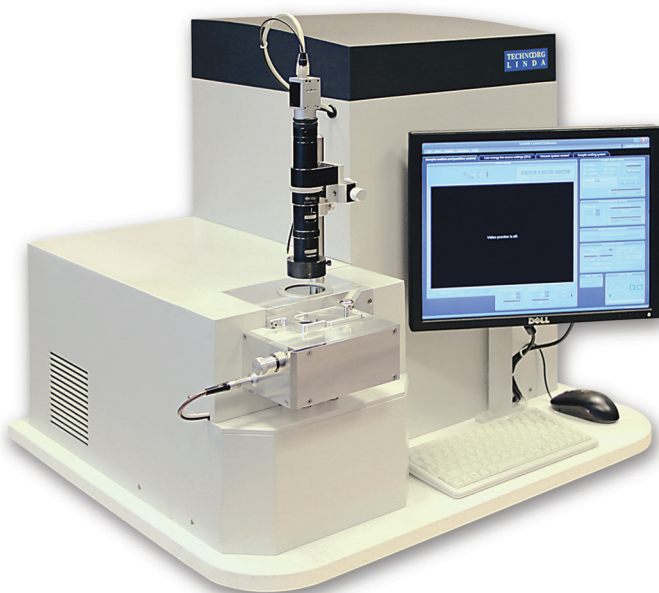
The Gentle Mill 3 is also suitable for final thinning of dimpled or thin (<25µm), planar, mechanically polished samples with its state-of-the-art low-energy Ion source.



### SC-1000 Sample Preparation System

**High-quality site-specific sample preparation in SEM applications.**

The SC-1000 model is equipped both with high- and low-energy ion sources. Rapid slope cutting with the high-energy ion gun followed by gentle surface cleaning with the low-energy ion gun provides cross-sectional SEM samples suitable for geological analysis, semiconductor failure analysis, and other analytical purposes. The system also provides an ion milling based solution for improving and cleaning mechanically polished SEM samples and preparation of damage-free surfaces for EBSD techniques.



### IV7 Sample Preparation System

**Rapid preparation of high-quality TEM/XTEM samples.**

The IV7 Universal Ion Mill is recommended to users developing new materials or new sample preparation methods. Due to its extremely high milling rate, it is optimal for studying hard-to-sputter materials, such as diamond, sapphire, etc. Its exclusive capability of producing damage- and artifact-free samples by low-energy ion bombardment provides a unique opportunity to study real nanostructures in synthesized and natural materials in all fields of technical sciences and materials research.



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